

Dual 4-input NAND buffer

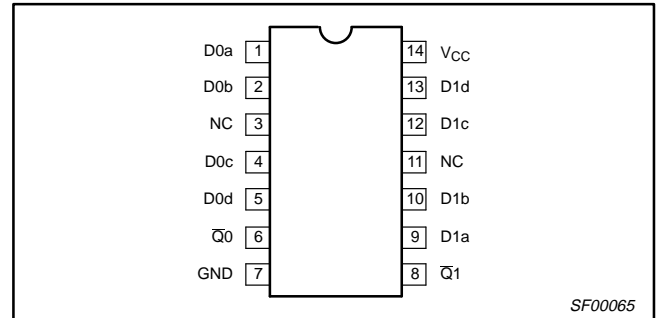
74F40

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F40	3.5ns	6mA

ORDERING INFORMATION

DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^{\circ}C$ to $+70^{\circ}C$
14-pin plastic DIP	N74F40N
14-pin plastic SO	N74F40D

PIN CONFIGURATION

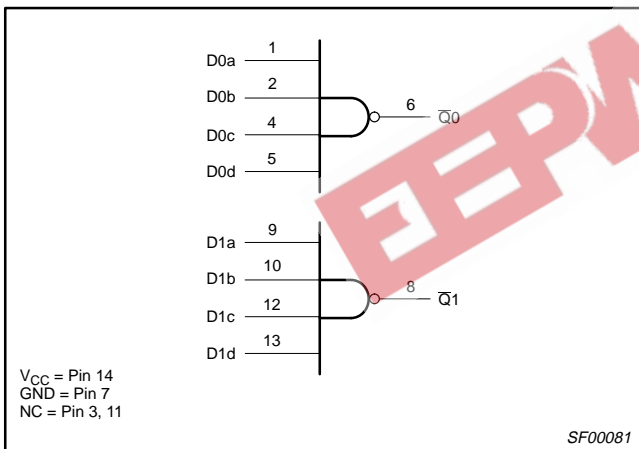


INPUT AND OUTPUT LOADING AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb, Dnc, Dnd	Data inputs	1.0/2.0	20μA/1.2mA
$\bar{Q}0, \bar{Q}1$	Data outputs	750/106.7	15mA/64mA

NOTE: One (1.0) FAST unit load is defined as: 20μA in the High state and 0.6mA in the Low state.

LOGIC DIAGRAM



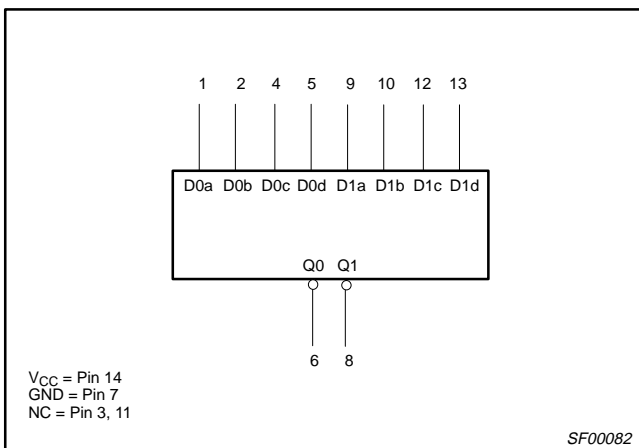
FUNCTION TABLE

INPUTS				OUTPUT
Dna	Dnb	Dnc	Dnd	$\bar{Q}n$
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	X	H
H	H	H	H	L

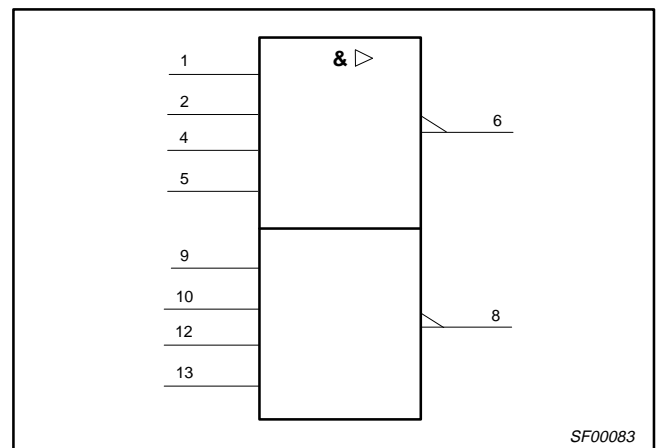
NOTES:

- H = High voltage level
- L = Low voltage level
- X = Don't care

LOGIC SYMBOL



IEC/IEEE SYMBOL



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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to V_{CC}	V
I_{OUT}	Current applied to output in Low output state	128	mA
T_{amb}	Operating free-air temperature range	0 to +70	°C
T_{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-15	mA
I_{OL}	Low-level output current			64	mA
T_{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT		
			MIN	TYP ²	MAX			
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = \text{MIN}$	$I_{OH} = -1\text{mA}$	$\pm 10\%V_{CC}$	2.5		V	
				$\pm 5\%V_{CC}$	2.7	3.4		
		$I_{OH} = -15\text{mA}$	$\pm 10\%V_{CC}$	2.0			V	
			$\pm 5\%V_{CC}$	2.0				
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}, V_{IH} = \text{MIN}$	$I_{OL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.55	V	
				$\pm 5\%V_{CC}$		0.42	0.55	
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$			-0.73	-1.2	V	
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7.0\text{V}$				100	μA	
I_{IH}	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$				20	μA	
I_{IL}	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$				-0.6	mA	
I_{OS}	Short-circuit output current ³	$V_{CC} = \text{MAX}$			-100	-225	mA	
I_{CC}	Supply current (total)	$V_{CC} = \text{MAX}$		$V_{IN} = \text{GND}$		1.75	4.0	mA
				$V_{IN} = 4.5\text{V}$		11	17	

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5\text{V}$, $T_{amb} = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

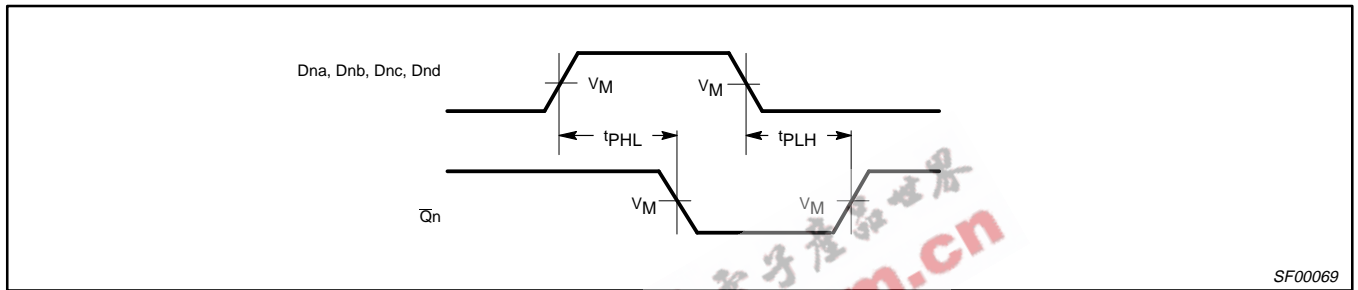
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			V _{CC} = +5.0V T _{amb} = +25°C C _L = 50pF, R _L = 500Ω			V _{CC} = +5.0V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF, R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay D _{na} , D _{nb} , D _{nc} , D _{nd} to \bar{Q}_n	Waveform 1	2.0 1.5	4.0 3.0	6.0 5.0	1.5 1.0	7.0 5.5	ns

AC WAVEFORMS



Waveform 1. Propagation Delay for Inverting Outputs

NOTE:

For all waveforms, V_M = 1.5V.

TEST CIRCUIT AND WAVEFORMS

Test Circuit for Totem-Pole Outputs

DEFINITIONS:
 R_L = Load resistor; see AC electrical characteristics for value.
 C_L = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.
 R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

Input Pulse Definition

family	INPUT PULSE REQUIREMENTS					
	amplitude	V _M	rep. rate	t _w	t _{TLH}	t _{THL}
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns